

Stanford

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Ph.D. Student in Electrical Engineering, admitted Autumn 2017

Publications

PUBLICATIONS

- **Spatially-Resolved Thermometry of Filamentary Nanoscale Hot Spots in TiO₂ Resistive Random Access Memories to Address Device Variability.** *ACS applied electronic materials*
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- **Ambipolar Thickness-Dependent Thermoelectric Measurements of WSe₂.** *Nano letters*
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- **Nanoscale temperature sensing of electronic devices with calibrated scanning thermal microscopy.** *Nanoscale*
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- **High Thermal Conductivity Insulators for Thermal Management in 3D Integrated Circuits** *IEEE ELECTRON DEVICE LETTERS*
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- **Approaching the quantum limit in two-dimensional semiconductor contacts.** *Nature*
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- **Improved gradual resistive switching range and 1000x on/off ratio in HfO_x PRAM achieved with a Ge₂Sb₂Te₅ thermal barrier** *APPLIED PHYSICS LETTERS*
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- **High-performance flexible nanoscale transistors based on transition metal dichalcogenides** *NATURE ELECTRONICS*
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- **Analysis of Field-Effect Passivation in Textured and Undiffused Silicon Surfaces** *PHYSICAL REVIEW APPLIED*
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2019; 12 (3)